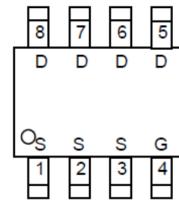
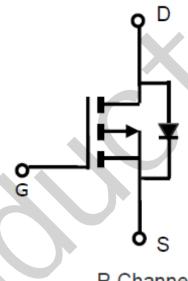


■ FEATURE

- ◆ -30V/-5.8A, $R_{DS(ON)}=38m\Omega$ (typ.) @ $V_{GS}=-10V$
- ◆ -30V/-4.0A, $R_{DS(ON)}=60m\Omega$ (typ.) @ $V_{GS}=-4.5V$
- ◆ Super high design for extremely low $R_{DS(ON)}$
- ◆ Exceptional on-resistance and Maximum DC current capability
- ◆ Full RoHS compliance
- ◆ SOP8 package design


 TOP VIEW
 SOP-8


■ DESCRIPTION

The SI9435BDY-T1-E3 is the P-Channel logic enhancement mode power field effect transistor is produced using high cell density advanced trench technology..

This high density process is especially tailored to minimize on-state resistance.

These devices are particularly suited for low voltage application, notebook computer power management and other battery powered circuits where high-side switching.

■ APPLICATIONS

- ◆ High Frequency Point-of-Load Synchronous
- ◆ Networking DC-DC Power System
- ◆ Load Switch

■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless otherwise noted)

Symbol	Parameter	Typical	Unit	
V_{DSS}	Drain-Source Voltage	-30	V	
V_{GSS}	Gate-Source Voltage	± 20	V	
I_D	Continuous Drain Current ($T_A=25^\circ C$)	$V_{GS}=10V$	-5.8	A
	Continuous Drain Current ($T_A=75^\circ C$)		-4.2	A
I_{DM}	Pulsed Drain Current	-20	A	
I_S	Continuous Source Current (Diode Conduction)	-2.0	A	
P_D	Power Dissipation	$T_A=25^\circ C$	2.05	W
		$T_A=70^\circ C$	1.5	
T_J	Operation Junction Temperature	150	$^\circ C$	
T_{STG}	Storage Temperature Range	-55~+150	$^\circ C$	
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	85	$^\circ C/W$	

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress rating only and functional device operation is not implied

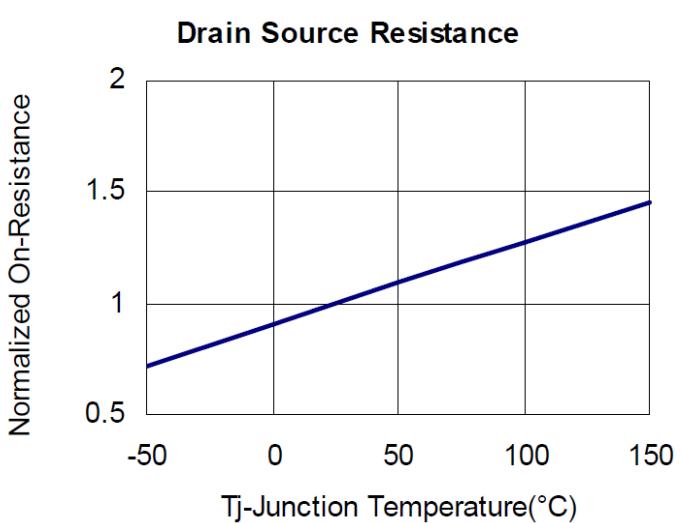
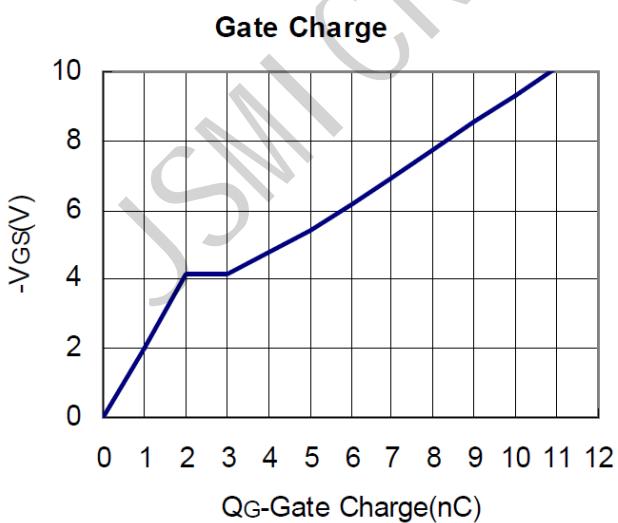
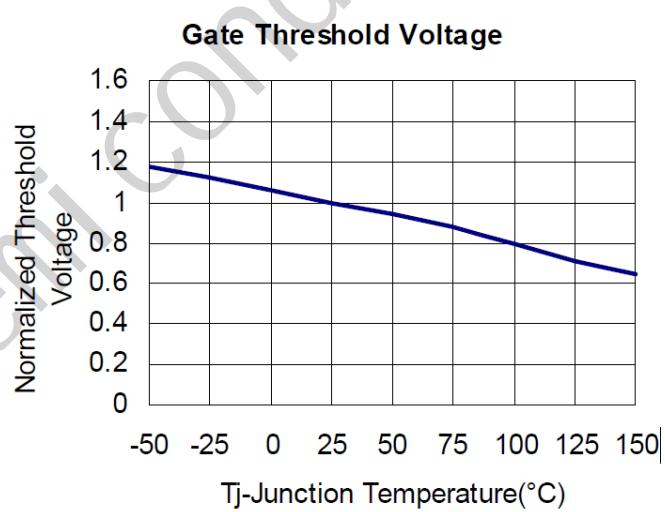
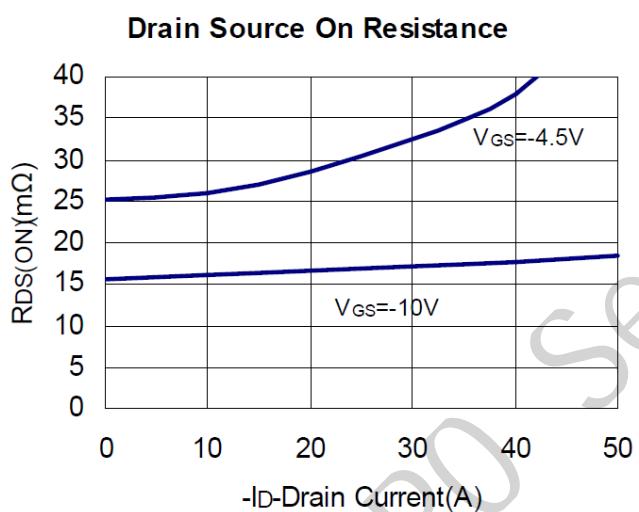
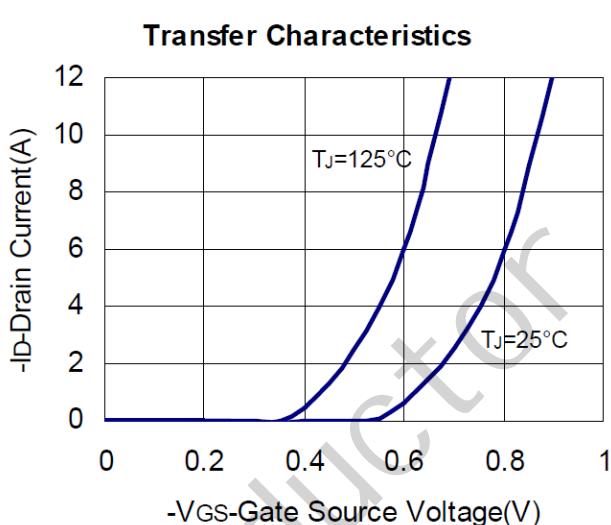
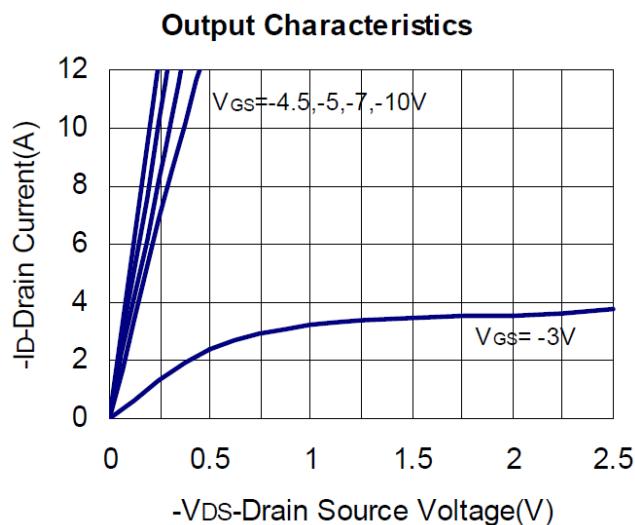
■ **ELECTRICAL CHARACTERISTICS**($T_A=25^\circ C$ Unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit	
Static Parameters							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30			V	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.0		-2.5	V	
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$			± 100	nA	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24V, V_{GS}=0$			-1	uA	
		$V_{DS}=-24V, V_{GS}=0$ $T_J=55^\circ C$			-5		
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=-10V, I_D=-10A$		38	48	$m\Omega$	
		$V_{GS}=-4.5V, I_D=-6.0A$		60	78		
Source-Drain Diode							
V_{SD}	Diode Forward Voltage	$I_S=-2.0A, V_{GS}=0V$		-0.7	-1.2	V	
Dynamic Parameters							
Q_g	Total Gate Charge	$V_{DS}=-20V$ $V_{GS}=-10V$ $I_D=-5.8A$		6.2		nC	
Q_{gs}	Gate-Source Charge			2.5			
Q_{gd}	Gate-Drain Charge			3.3			
C_{iss}	Input Capacitance	$V_{DS}=-15V$ $V_{GS}=0V$ $f=1MHz$		640		pF	
C_{oss}	Output Capacitance			270			
C_{rss}	Reverse Transfer Capacitance			103			
$T_{d(on)}$	Turn-On Time	$V_{DS}=-15V$ $I_D=-5A$ $V_{GEN}=-10V$ $R_G=3.3\Omega$		9.2		ns	
T_r				16.5			
$T_{d(off)}$	Turn-Off Time			21.3			
T_f				21.5			

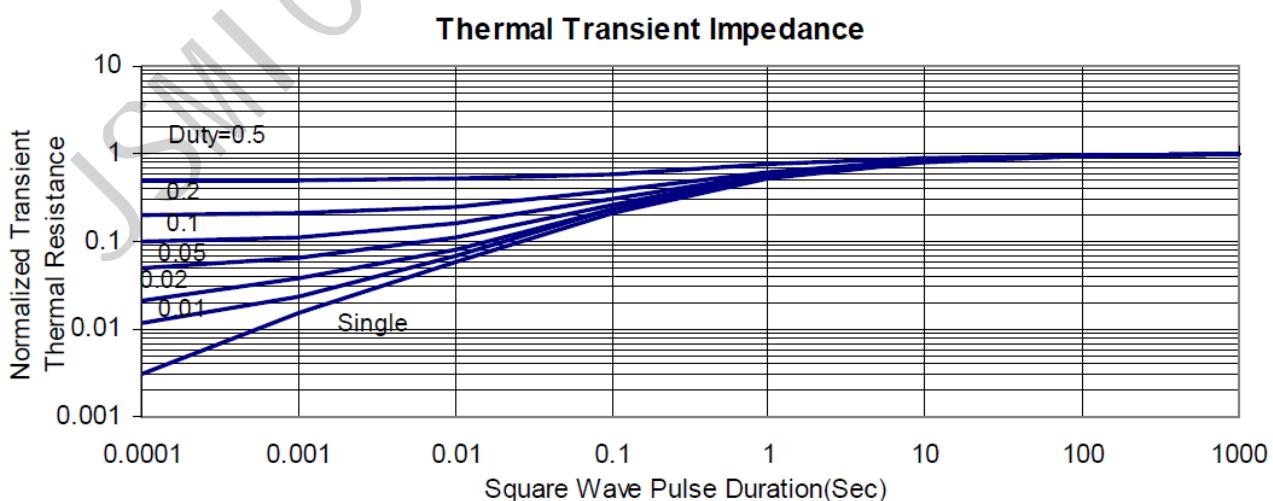
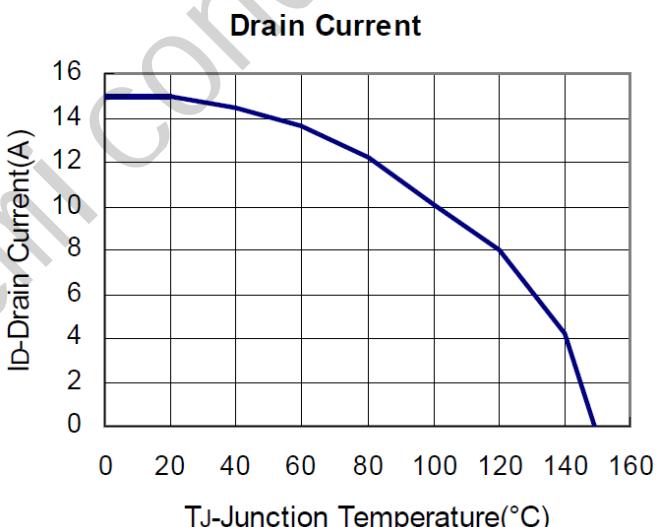
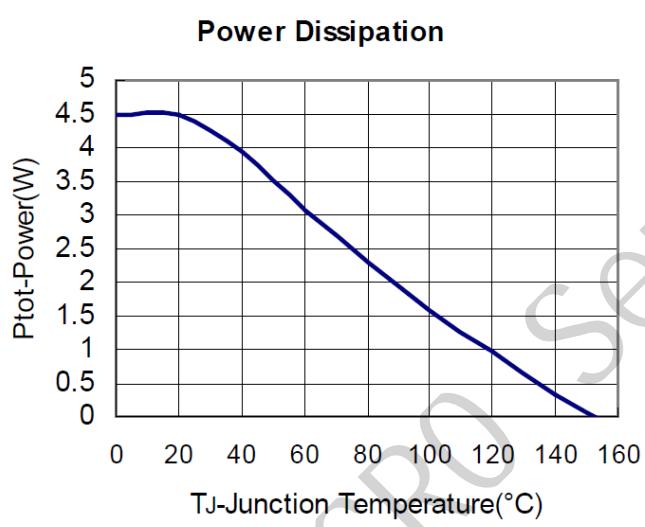
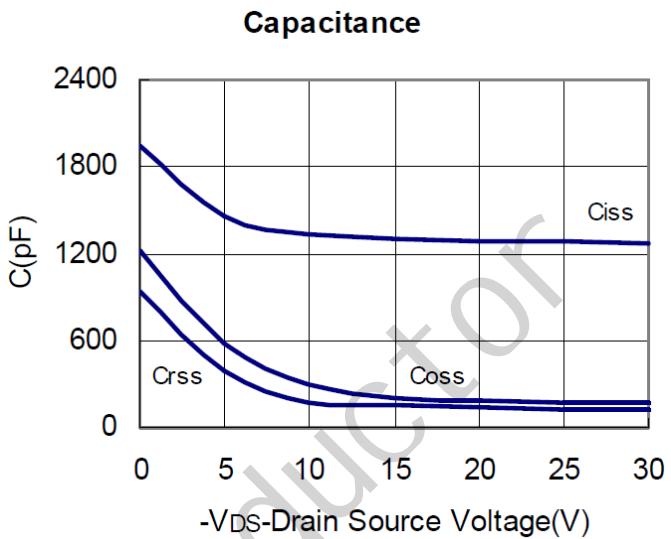
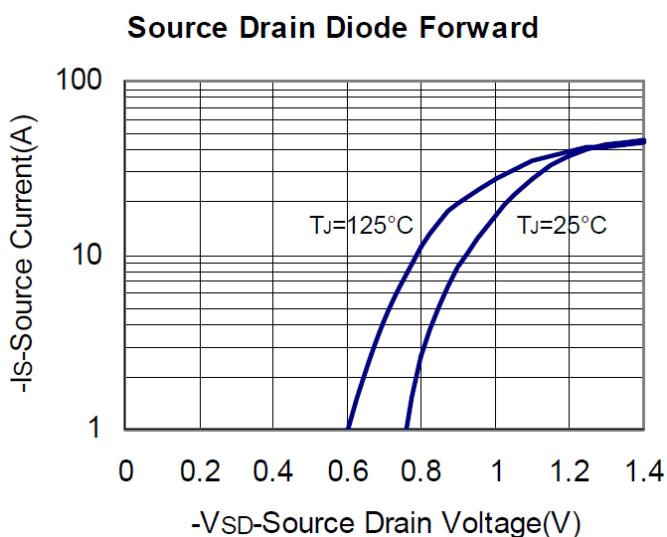
Note: 1. Pulse test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

2. Static parameters are based on package level with recommended wire bonding

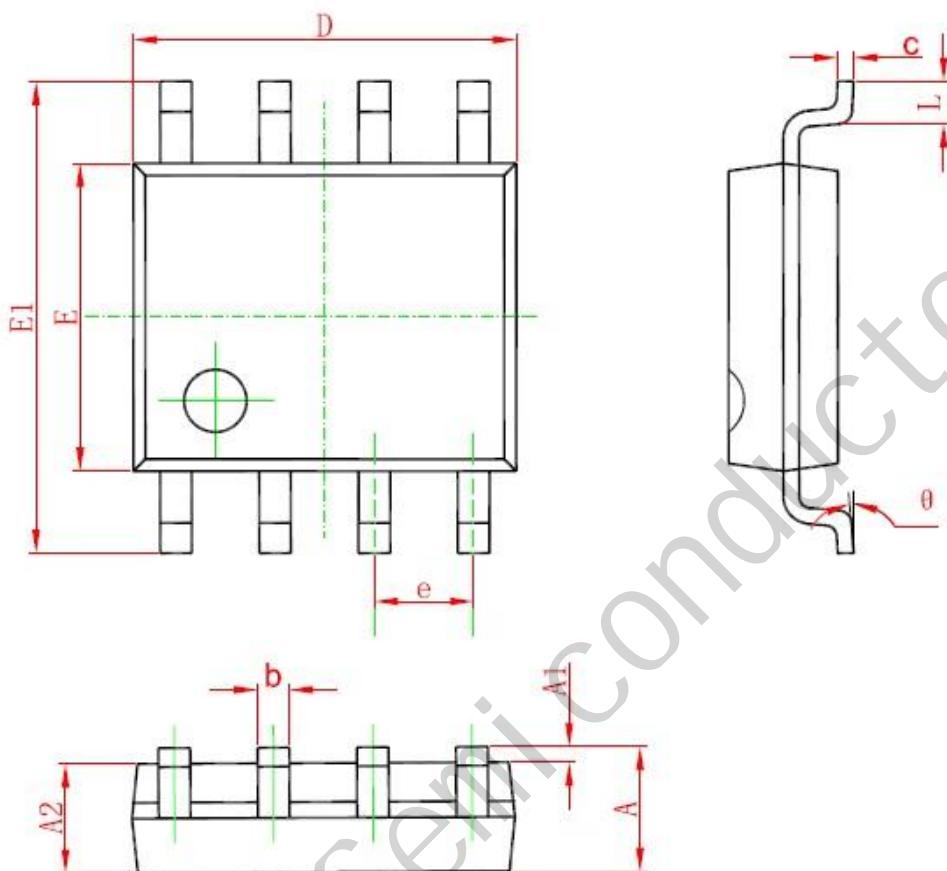
■ **TYPICAL CHARACTERISTICS (25°C Unless Note)**



■ **TYPICAL CHARACTERISTICS (continuous)**



■ SOP8 PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°